

# AIS-E2-CV1

## Environment Test Report

Report NO: 13I020022

Summary	<input checked="" type="checkbox"/> <b>Pass</b>  <input type="checkbox"/> <b>Fail</b>  Note : There is/are ____ defect(s) not list in the report, please check it in the DTS Website.  <input type="checkbox"/> <b>Pass with Deviation</b>  Comment:
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Issue date	Approval	Test Engineer
2013-07-31	Tom Lin	Jerry Chen

# Configuration of EUT

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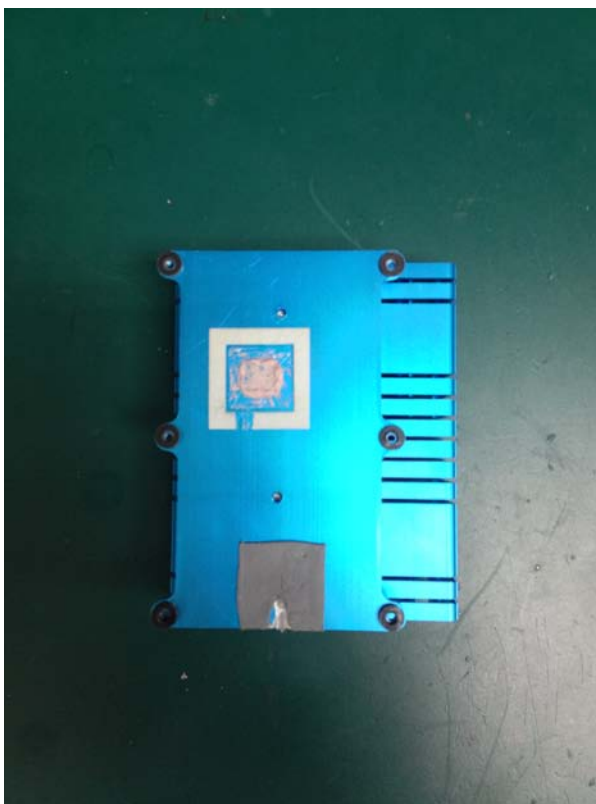
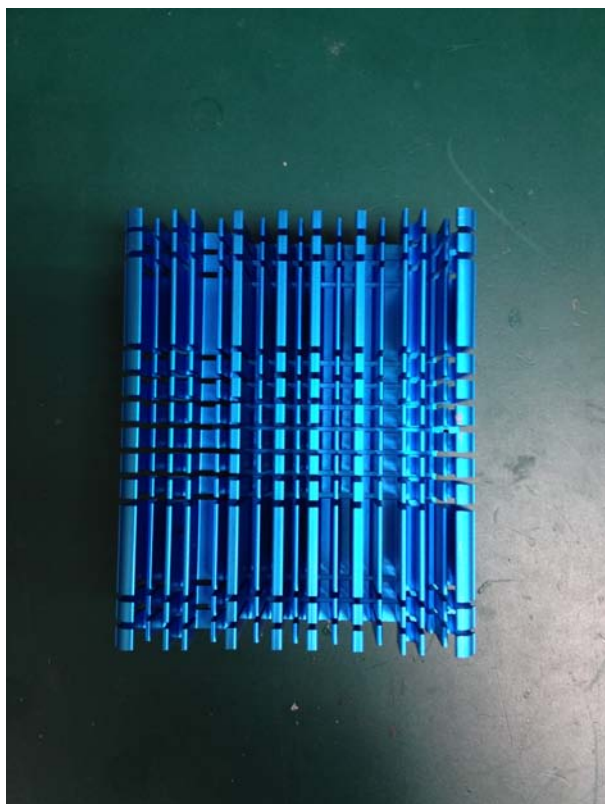
## Testing Result

Num	Test item list	Result	Remark
1	Temperature rise test	Pass	
2	Temperature cycle operation test	Pass	
3	High temperature storage test	Pass	
4	Low temperature storage test	Pass	
5	Humidity test	Pass	
6	Cold start and hot start test	Pass	

# Configuration of EUT

Num	Item	Spec
1.	<b>Control Box:</b>	AIS-E2-CV1 A1.0
	1. Main Board	EMB-CV1
	2. BIOS Ver.	EMB-CV1 R1.6 (10/23/2012)
	3. CPU	Intel Atom D2550 B3 Processor / 1.86GHz
	4. Memory	ELPIDA J2108BCSE-DJ-F / DSL DDR3 1066 / 4GB
	5. HDD	TOSHIBA MK1676GSX SATA 2.5 HDD 160GB
	6. Test Software	Windows 7 / Run PassMark Burn In Test 7.0 Pro
2.	<b>AC Adapter</b>	FSP. FSP084-DMAA1 Output: 12V; 7.0A (84W MAX)

## Heat Sink



# Temperature rise test

**Test Date:** 07-30-2013

**Test Product:** AIS-E2-CV1

**Test Site:** AAEON QE Dept.

**Test Standard:** Reference EN 61131-2(94), UL508 (94)

**Temperature Measurement:**

40 Channel Thermal Recorder: (YOKOGAWA Inc.)  
 Model: DA100-13-1D  
 Date of Calibration: 10/08/12  
 Serial Number: 12A323190

**Test Condition:**

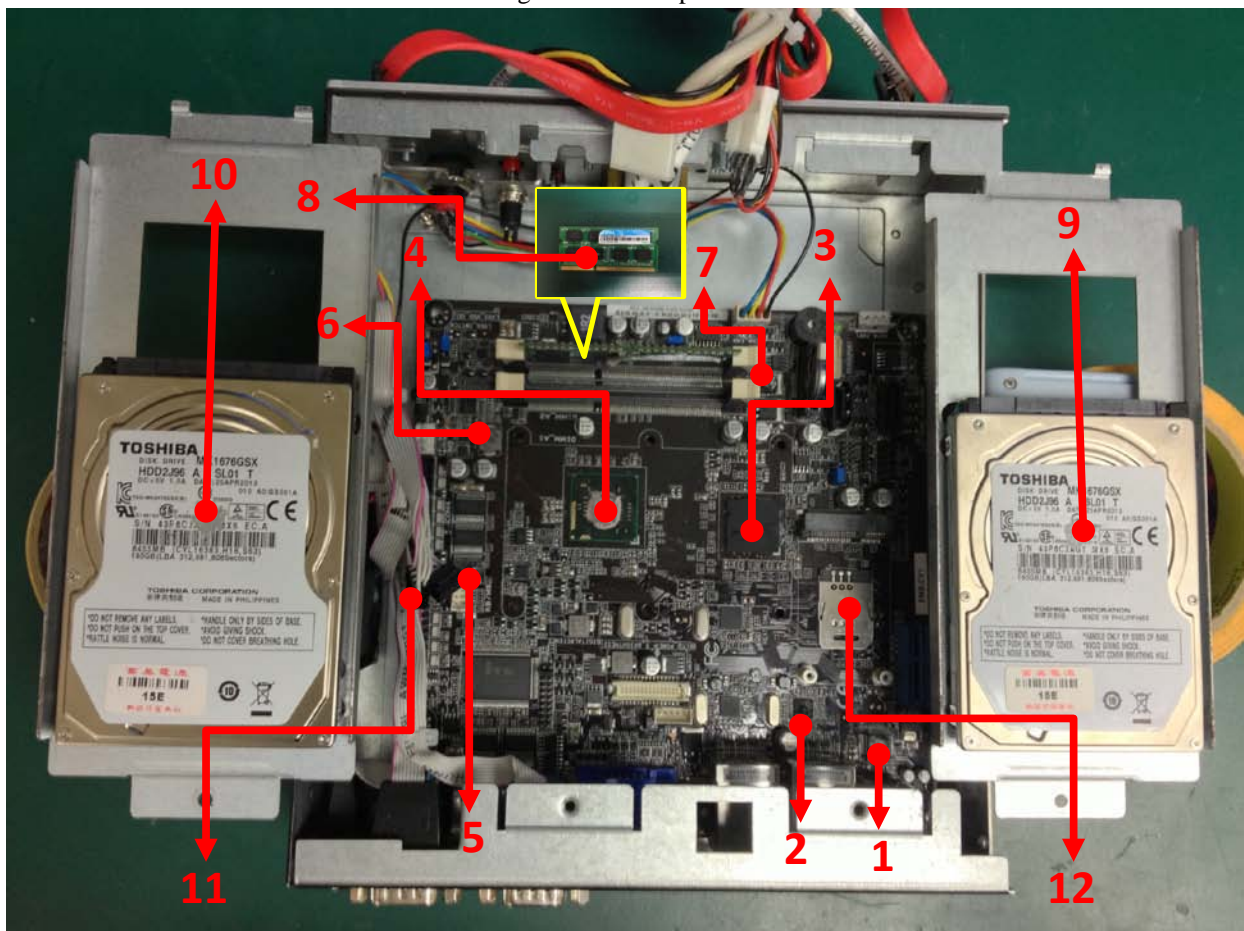
Ambient temperature: 45°C  
 Continuous running till thermal stability (within less than 1°C)

**Test Software:**

Windows 7 / Run PassMark Burn In Test 7.0 Pro

**Terminal Recorder:**

Measuring Thermal Couple Position :



# Temperature rise test



AIS-E2-CV1

Point	Temp. Stage(°C)	Spec	45	25	Note
<b>AIS-E2-CV1</b>					
01. AU1 - C.S VT1708S EUP (CD) LQFP48 VIA TAIWAN/CU-WIRE [HF].SMD		100	65.6	45.6	
02. LU1 - (TF)IC.PCI-express.Gigabit Ethernet.REALTEK.RTL8111E-VL-CG		100	51.6	31.6	
03. SU1 - (TF)IC.SMD.NM10 Express Chipset.INTEL.CG82NM10.SLGXX		115	54.7	34.7	
04. U1 - (TF)INTEL Cedarview CPU.2.13Ghz.D2700		100	65.1	45.1	
05. OU11 - (TF)IC.SMD.SSOP RS232 Driver ESD 15KV.AD.ADM213EARSZ		100	54.5	34.5	
06. PL4 - INDUCTOR 2.2UH/8A CYNTEC/PCMB063T-2R2MS [HE].SMD		125	58.5	38.5	
07. PQ404 - (TF)PWR.SMD.3P.N-Channel MOSFET.NIKO-SEM.P0903BDL		125	62.2	42.2	
08. Memory - Chipset		95	63.3	43.3	
09. HDD-1		63	48.8	28.8	
10. HDD-2		63	50.4	30.4	
11. Control Box Inside Air Temperature – 1		N/A	48.8	28.8	
12. Control Box Inside Air Temperature – 2		N/A	46.7	26.7	
13. Control Box External Surface - 1		N/A	46.2	26.2	
14. Chamber Air Temperature		N/A	45	25	

**Note(\*):**

1. "Tc" indicates the component's case maximum temperature value specified in its datasheet.
2. "Tm" indicates the measured Tc value under working environmental temperature within product specification.
3. **Judgment Criteria:**

# Temperature rise test

- **Fail** :  $T_m > T_c$ ; The measured value is over specification.
- **Margin Pass** :  $T_c > T_m > T_c - 5^\circ\text{C}$ ; The measured value is within specification with margin.  
It is strongly recommended to add thermal dissipation design for better reliability.
- **Pass** :  $T_m < T_c - 5^\circ\text{C}$ ; The measured value is with safety margin.

## 4. Defect NO.

### Sample Configuration & Quantity Under Test:

Quantity: 1 (AIS-E2-CV1)

### Test Result:

No issues were found during the temperature rise test.

# Temperature cycle operation test

**Test Date:** 07-19 ~ 22-2013

**Test Product:** AIS-E2-CV1

**Test Site:** AAEON QE Dept.

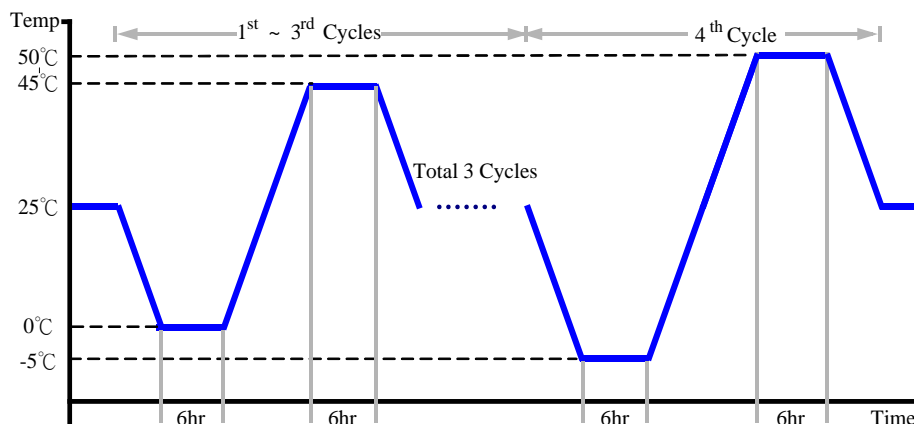
**Test Standard:** Refer to IEC68-2-14 Testing procedures  
 Test N: Change of temperature Test

**Test Equipment:**

Programmable Temperature & Humidity Chamber (K.SON. INS. TECH. CORP.)  
 Model: THS-B6T-150+LN2  
 Date of Calibration: 03/07/13  
 Serial Number: 6487KT

**Test Condition:**

1. Test Low Temperature: 0°C (1~3 cycles)  
 -5°C (4<sup>th</sup> cycle)
2. Test High Temperature: 45°C (1~3 cycles)  
 50°C (4<sup>th</sup> cycle)
3. Test dwell time: 6Hrs
4. Temperature slope: 2°C/min
5. Test cycle: 4 cycles
6. Test Environment Curve:



**Sample Configuration & Quantity Under Test:**

Quantity: 1 (AIS-E2-CV1)

**Test Result:**

No issues were found during the temperature operation cycle test.

# High temperature storage test

**Test Date:** 07-22 ~ 24-2013

**Test Product:** AIS-E2-CV1

**Test Site:** AAEON QE Dept.

**Test Standard:** Refer to IEC 68-2-2 Testing procedures  
Test Bb: Dry Heat Test (Non-operation)

**Test Equipment:**

Programmable Temperature & Humidity Chamber (K.SON. INS. TECH. CORP.)  
Model: THS-B6T-150+LN2  
Date of Calibration: 03/07/13  
Serial Number: 6487KT

**Testing Item:**

1. Test Temperature: 60°C
2. Test Times: 48Hrs
3. Test Software: Windows 7 / Run PassMark Burn In Test 7.0 Pro
4. Test Environment Curve:



**Sample Configuration & Quantity Under Test:**

Quantity: 1 (AIS-E2-CV1)

**Test Result:**

No issues were found after the high temperature storage test.



# Low temperature storage test

**Test Date:** 07-24~ 26-2013

**Test Product:** AIS-E2-CV1

**Test Site:** AAEON QE Dept.

**Test Standard:** Refer to IEC 68-2-1 Testing procedures  
 Test Ab: Cold Test (Non-operation)

**Test Equipment:**

Programmable Temperature & Humidity Chamber (K.SON. INS. TECH. CORP.)  
 Model: THS-B6T-150+LN2  
 Date of Calibration: 03/07/13  
 Serial Number: 6487KT

**Testing Item:**

1. Test Temperature: -20°C
2. Test Times: 48Hrs
3. Test Software: Windows 7 / Run PassMark Burn In Test 7.0 Pro
4. Test Environment Curve:



**Sample Configuration & Quantity Under Test:**

Quantity: 1 (AIS-E2-CV1)

**Test Result:**

No issues were found after the low temperature storage test.

# Humidity test

**Test Date:** 07-26 ~ 29-2013

**Test Product:** AIS-E2-CV1

**Test Site:** AAEON QE Dept.

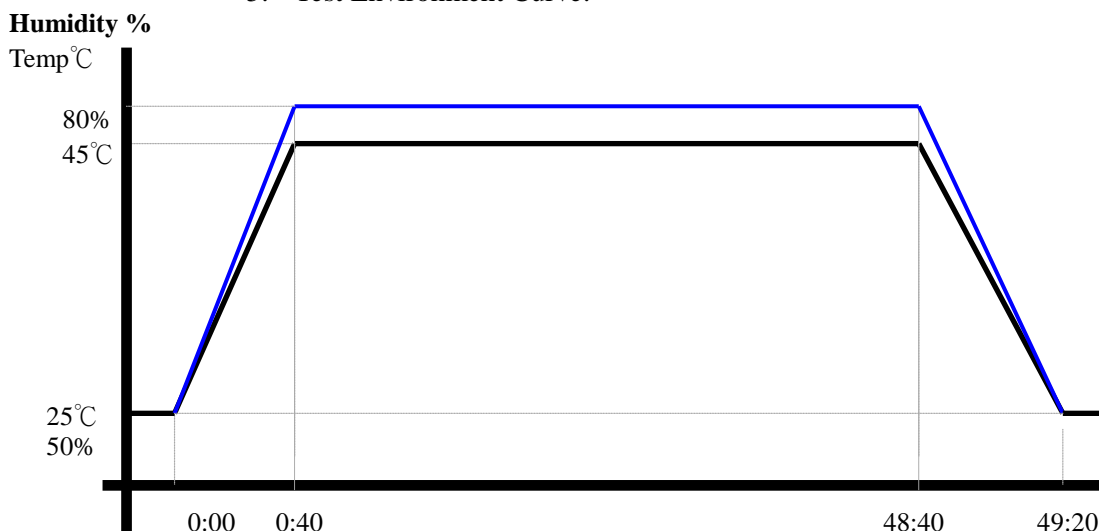
**Test Standard:** Refer to IEC 68-2-3 Testing procedures  
 Test Ca: Damp heat, steady state (Non-operation)

**Test Equipment:**

Programmable Temperature & Humidity Chamber (K.SON. INS. TECH. CORP.)  
 Model: THS-B6T-150+LN2  
 Date of Calibration: 03/07/13  
 Serial Number: 6487KT

**Testing Item:**

1. Test Temperature: 45°C
2. Test Humidity: 80% RH
3. Test Times: 48Hrs
4. Test Software: Windows 7 / Run PassMark Burn In Test 7.0 Pro
5. Test Environment Curve:



**Sample Configuration & Quantity Under Test:**

Quantity: 1 (AIS-E2-CV1)

**Test Result:**

No issues were found after the humidity storage test.

# Cold start and hot start test

**Test Date:** 07-29~30-2013

**Test Product:** AIS-E2-CV1

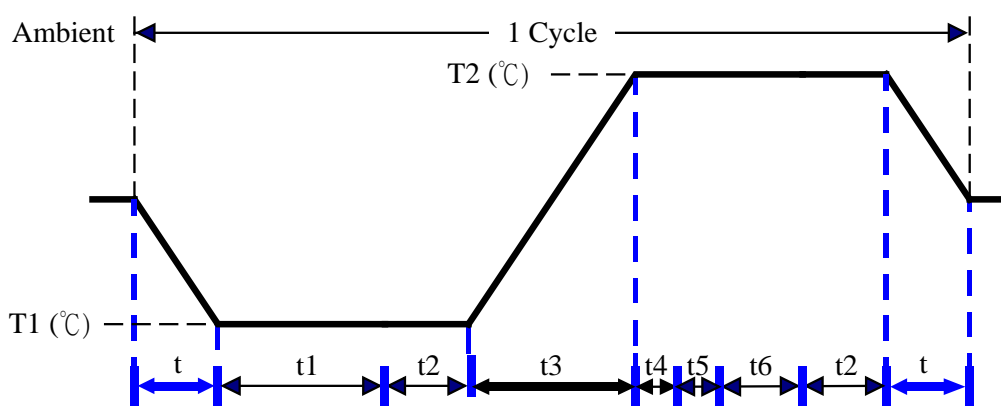
**Test Site:** AAEON QE Dept.

**Test Standard:** Refer to IEC 68-2-14 Testing procedures  
 Test N: Change of temperature Test

**Test Equipment:**

Programmable Temperature & Humidity Chamber (K.SON. INS. TECH. CORP.)  
 Model: THS-B6T-150+LN2  
 Date of Calibration: 03/07/13  
 Serial Number: 6487KT

**Test Condition:**



Parameters	Description
T1	-5°C
T2	50°C
t1	4 hrs
t2, t6	2 hrs
t4, t5	1hrs
t, t3	2°C/min
n (Cycle)	1

t = temprature slope  
 t , t1, t6: Power Off  
 t2: Power on/off test 5 times (on 2 min / off 5min)  
 t3, t4: Run PassMark BurnIn Test 7.0 Pro  
 t5: Win 7 Software restart test 3 times  
 Test Software: Windows 7

**Test Result:**

- a. No issues were found during the cold start test.
- b. No issues were found during the hot start test.